

Characterization of Interfaces Between the Metal Film and Silicon Carbide Semiconductor = Metallkontakti ja ränikarbiidi vahelise liidespinna karakteriseerimine

Ziko, Mehadi Hasan 2021 <https://digikogu.taltech.ee/et/Item/34be534c-63e8-4013-b271-eaf1a7cb22e7>
https://www.eester.ee/record=b5471196*est <https://doi.org/10.23658/taltech.52/2021>